A nharm onic vs. relaxational sound dam ping in glasses: II. V itreous silica

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(D ated: A pril 14, 2024)

The tem perature dependence of the frequency dispersion in the sound velocity and damping of vitreous silica is reanalyzed. Them ally activated relaxation accounts for the sound attenuation observed above 10 K at sonic and ultrasonic frequencies. Its extrapolation to the hypersonic regim e reveals that the anham onic coupling to the them albath becomes important in B rillouin-scattering m easurements. At 35 G H z and room temperature, the damping due to this anham onicity is found to be nearly twice that produced by therm ally activated relaxation. The analysis also reveals a sizeable velocity increase with temperature which is not related with sound dispersion. A possible explanation is that silica experiences a gradual structural change that already starts well below room temperature.

PACS num bers: 63.50.+ x, 78.40.Pg, 62.80.+ f, 78.35.+ c

I. IN TRODUCTION

In the rst paper of this series (I), the hypersonic attenuation of highly densi ed silica glass, d-SiO 2, was investigated. It was found that in that m aterial the dam ping of hypersound is completely dom inated by its anharm onic interaction with the therm ally dom inant modes. In the present paper we consider the corresponding situation in usual vitreous silica, v-SiO₂, for which a large quantity of high quality data is already available in the literature. In the early 1950's, ultrasonic absorption peaks in function of the tem perature T were rst observed in v-SiO2. These were described by Anderson and Bommel in terms of a phenom enological Maxwellm odel [1]. Following the discovery of the key role played by two-level system s (TLS) in producing the anom alous therm alproperties of glasses [2, 3], it became clear that these should also be invoked in the description of acoustic relaxation. A theory including both resonant and relaxational sound dam ping produced by tunneling was developed by Jackle [4]. It was then extended to higher tem peratures by including in the description the classical jumps over the energy barrier separating the wells of TLS [5]. The presently accepted model for thermally activated relaxation (TAR) includes a distribution of asym metric double-well potentials, as discussed by G ilroy and Phillips [6].

The simple extrapolation of this behavior to GHz frequencies, i.e. to the hypersonic regime, has sometimes been presented as an appropriate description of the observed phenomena, e.g. in [7, 8] or [9]. However, it has also been recognized that TAR m ight not always be sufcient to account for sound dispersion and damping. A speci c example has been discussed in the case of vitreous germania, $G \in O_2$ [10]. The results presented in (I) strongly suggest that v-SiO₂ should be an excellent candidate to search for a possible anharm onic contribution to the hypersonic attenuation.

The paper is organized as follows. In Section II the phenomenology of TAR is reviewed to formulate a de-

scription that can reasonably be extrapolated to su ciently high-T and to B rillouin-scattering frequencies. In Section III this formalism is applied to available high quality sonic and ultrasonic data on v-SiO₂, covering more than four orders of magnitude in the frequency . The model parameters that are thus extracted are then used in Section IV to estimate the TAR contributions to both velocity dispersion and damping at Brillouinscattering frequencies. The anham onic contribution can then be extracted from the total signal. It is analyzed in terms of a mean therm almode relaxation time th in Section V. Interestingly, this time is found to be about an order of magnitude longer than that of densi ed silica glass, d-SiO₂. Section V I presents a synthesis of the above analysis for the entire range of , from ultrasonic to Brillouin-scattering frequencies. A part of that analysis concerns the velocity changes with T.We nd an anom alous increase of the bare velocity v_1 with T, nearly the same in v-SiO₂ and d-SiO₂. This unrelaxed velocity, v_1 , is obtained after subtraction of the velocity changes produced by both therm ally activated relaxation and anharmonicity. The T-dependence of v_1 suggests that silica experiences a progressive structural change with increasing T. Section VII is a discussion, which mentions the crossoversbetween the various frequency regimes, considers the suitability of power laws for the description of the dependence of the damping on , and evoques possible extension to other glasses.

II. THE PHENOM ENOLOGY OF THERMALLY ACTIVATED RELAXATION

We consider an assembly of defects represented by double-well potentials that are separated by barriers of height V and whose depths di er by the asymmetry . The energies V and are random ly distributed according to a distribution P (;V) d dV to be discussed below. The system is thought to hop continuously between

the wells. The energy di erence between the wells is coupled to the strain e of a sound wave of angular frequency

2 by a deform ation potential = $\frac{1}{2}$ @ =@e.Owing to the delayed energy exchanged in hopping, this produces the dissipation of the sound wave. This situation has been described in great details elsewhere [5, 6, 11, 12]. To an excellent approximation, it leads to a relaxational contribution to the internal friction given by

$$Q_{rel}^{1} = \frac{2}{v^{2}T} \begin{bmatrix} Z_{1} & Z_{1} \\ d & dV P (;V) \text{ sech}^{2} \frac{2}{2T} \frac{1}{1+2^{2}} \end{bmatrix}$$
(1a)

In this expression, is the material density, v is the velocity of sound, and T is in energy units. W e remark that both

and v depend on the polarization of the acoustic wave, longitudinal (LA) or transverse (TA). In this writing, V is restricted to positive values while the distribution is symmetric in .W ealso note that P (;V)d dV is a density, i.e. a number per unit volume. The associated velocity change, which follows from the K ramers-K ronig relation, is given by

$$\frac{v}{v}_{rel} = \frac{1}{2} \frac{2}{v^2 T} \frac{z}{1} \frac{z}{1}$$

In these equations, is the relaxation time for hopping within the double well. It is given by

$$= _{0} \exp \frac{V}{T} \operatorname{sech} \frac{1}{2T} ; \qquad (2)$$

where $_0$ is the inverse of an attempt frequency, as shown in detaile.g. in [12].

The key in applying these expressions is to use a reasonable distribution P (;V). For small and V the distribution is often replaced by a constant P. This is suggested by the T-dependence of the specic heat at low T which only probes low values of and V [13]. Of course, a constant P cannot be extended to high values of and V as this leads to a diverging integral density of defects which is unphysical. A reasonable guess for P (;V) can be obtained with the help of the softpotential model (SPM) [14]. That model is characterized by a distribution of random dimensionless cubic and quadratic coe cients, and respectively, by an energy scale of the potential E_0 , and by a characteristic crossover energy W E_0 [14]. We are only interested here in the region < 0 with 1 jj ² which gives double wells with barriers centered at the origin of the soft mode coordinate x. As shown in [15], owing to the latter choice, the variables and are not statistically independent. This leads to a sea-gull singularity in their distribution, P(;) = $\frac{1}{2}j P_0(;)$, where P₀(;) is nite near the origin. For the range of values of interest here, one has $= E_{0\frac{1}{P-2}} j j^{3-2}$ and $V = \frac{1}{4}E_0 j j^2$. The deformation potential of the SPM is also function of jjwith $^2_{\text{SPM}}$ / j j as de ned in [16] and further explained in [17]. The terms ²P (;V)d dV of (1a) are transformed into $^2_{\text{SPM}}$ P (;)d d in the SPM.Using the Jacobian $\frac{1}{2}$ (;V)= $\frac{1}{2}$ (;)j = $E_{0}^{2} \frac{1}{2^{p}} \frac{1}{2}$ j $\frac{1}{2^{p}}$, one nds that P (;V) / V $^{1=4}$ P $_0$ (;) [16]. This was already used by K eilet al. [18] who selected a distribution P (V)

proportional to V times a gaussian. These authors experimentally found that indeed is very near 1/4 in the case of silica.

For convenience, and for lack of di erent com pelling indications, we assume that the distribution can be factored into

$$P(;V) = f()g(V)$$
: (3)

Forg (V), inspired by [16] and [18], we use the norm alized form

$$g(V) = N_g \frac{1}{V_0} \frac{V}{V_0} \exp \frac{1}{2} \frac{V^2}{V_0^2}$$
 : (4a)

Since < 1, this expression is integrable. The norm N_g is selected so that g(V) integrates to 1. This gives

$$N_{g}^{1} = x \exp(\frac{1}{2}x^{2})dx = (1) U_{2}^{1} ;0) :$$
(4b)

The function U (a;0) is the parabolic cylinder function [19]. As explained in the following Section, our independent analysis of a collection of data larger than that used in [18] also leads to very close to 1/4. This provides a solid support for this particular choice of g(V). For f() we use a simple gaussian, rather similar to the gaussian cut-o of the linear asymmetry coe cient D₁ used by G il et al. [20]. Indeed, D₁ / jj/ V ¹⁼⁴, so that a gaussian in D₁ is very close to one in , the power of V connecting the two variables being quite sm all. This functional form for f() was already employed succesfully by Bonnet [21]. It is written

$$f() = N_f f_0 \exp \frac{1}{2} \frac{2}{c_c^2}$$
; (5a)

where f_0 is de ned by the norm alization condition that the integral of f () equals f $_0V_0$. The norm N $_{\rm f}$ is then

dim ensionless and given by

$$N_{f}^{1} = \sum_{1}^{Z_{1}} \exp(\frac{1}{2}x^{2}) dx = \frac{p}{2} = ;$$
 (5b)

where we de ned

$$V_0 = _{\rm C}$$
; (6)

c being the cut-o value of the asymmetry. We nally rem ark that with the above de nitions, the integral density of defects is

	Z 1	Ζ 1				
Ν	d		$dV P (;V) = f_{0}$	₀ V ₀ :	(7)	0
	1	0				

To complete the calculation, we now introduce (4) and (5) into (1), and use (2). In performing the integrals in (1), we make the same approximation as in [6] that sech (=2T) is replaced by 1 for j j < 2T and by zero otherwise. This eliminates the sech factors in (1) and (2) and simply replaces the limits of integration on by 2T. It is convenient to de ne a dim ensionless constant

C
$${}^{2}f_{0}N_{g} = v^{2}$$
 : (8)

ne obtains

$$Q_{\text{rel}}^{1} = C \qquad \frac{p_{\overline{2}T}}{c} \cdot \frac{1}{T} \frac{Z_{1}}{0} \cdot \frac{V}{V_{0}} \qquad \exp \qquad \frac{1}{2} \frac{V^{2}}{V_{0}^{2}} \cdot \frac{0}{1 + \frac{2}{0}} \frac{\exp(V=T)}{\exp(2V=T)} \, dV \quad ; \tag{9a}$$

$$\frac{v}{v}_{rel} = \frac{1}{2}C \qquad \frac{p}{2T} \frac{1}{c} \frac{z}{T} \frac{1}{v} \frac{z}{v_0} \qquad \exp \qquad \frac{1}{2}\frac{v^2}{V_0^2} \frac{1}{1 + \frac{2}{v} \frac{2}{0}\exp(2V=T)} dV ; \qquad (9b)$$

where (z) is the error function,

(z)
$$\frac{2}{p=}^{2} \exp(x^{2}) dx$$
: (10)

For the purpose of comparison with literature results, it will be useful to relate the value of C with the \tunneling strength" de ned by C $P^{2} = v^{2}$ in the usual tunneling m odel [11, 16, 22]. G iven the distribution (4), one cannot strictly de ne P, but this does not prevent de ning C in a consistent manner [16]. We calculate this for $=\frac{1}{4}$. We use ${}^{2}_{\text{SPM}} = \frac{1}{2}$ ${}^{2}j$ j and C = ${}^{2}P_{0}$ ${}^{7=2}_{\text{L}} = W$ v^{2} from [16], where ${}^{2}_{\text{L}}$ $W = E_{0}$. Introducing these de nitions into $^{2}_{\text{SPM}} P(;) d d = ^{2}P(;V) d dV$, and using (8), we not in the limit of small and V,

$$C = \frac{r}{2} \frac{W^{3=4}V_0^{1=4}}{c} C :$$
 (11)

Inform ation on the num erical handling of Eqs. (9) and our choice of suitable thing parameters are found in Appendix A.

III. ANALYSIS OF SONIC AND ULTRASONIC RELAXATIONAL DATA

It is generally agreed that sonic or ultrasonic dam ping at tem peratures above 10 K is dom inated by thermally activated relaxation. To obtain the model param eters V_0 , $_c$, and $_0$ entering Eqs. (9), it is necessary

to analyze acoustic results over a su ciently large range of frequencies , this up to high ultrasonic frequencies. It in plies com paring data from various sources and generally acquired with di erent measurement techniques. TAR leads to a peak in Q_{rel}^{1} as observed by Anderson and Bommel in ultrasonic pulse-echomeasurements [1]. These authors report precise data obtained on the TAmode of vitreous silica at = 20 M Hz. This is one of the curves that will be used for our analysis, as displayed in Fig.1. O ther high-frequency data were measured using the Bragg di raction of light, [23] in a set-up sim ilar to the original Debye-Sears experiment [24]. Damping results at ' 200 MHz on both LA- and TA-modes have been obtained in that manner [23]. From these, and from results presented in [25], it is clear that LAand TA-m odes lead to identical Q 1 peak shapes. This in plies that similar distributions of defects are active in the damping of all acoustic waves, independently from their polarizations. We use the data on the LA-mode at 207 MHz from [23], also shown in Fig.1. The independence from polarization allows including in the evaluation sonic frequency results acquired on macroscopic vibrational modes, such as in vibrating reed measurements. We use the data at = 11.4 kHz of Classen, as reported in [12]. This curve is also displayed in Fig.1. Results at interm ediate frequencies were collected using com posite oscillators, at 660 kH z on the LA-m ode in [6], and at 180 kH z on a torsionalm ode in [18]. A s rem arked in [18], this particular method can easily lead to instrum ental background-loss contributions. This m ight have

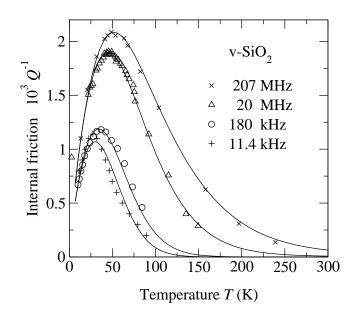


FIG.1: The data points are internal friction results on v-SiO₂ taken from the literature, [23], [1], [18], and [12] in order of decreasing frequency. The solid lines show our adjustment to Eq. (9a) as explained below.

been the case in [6], as suggested from data on other glasses presented by the same authors in [26] which show long absorption tails at high T. This notion is also supported by ts that are explained below. Hence, it is the 180 kHz data from [18] which is included in Fig.1. With these four curves, the analysed data covers more than four decades in with a nearly linear progression in log.

The curves shown in Fig. 1 have been simultaneously adjusted to Eq. (9a), allowing for each m easurement an independent coupling parameter C. In the Marguardt-Levenberg routine used to this e ect, the weights have been adjusted so that each curve had approxim ately the same weight, independently from the number of data points at each particular frequency. The excellent results of this t, with xed at 1/4, are illustrated by the solid lines in Fig. 1. The distribution param eters corresponding to these lines are $V_0 = 659$ 19 $K, \log_{10} 0 =$ 12:2 0:14 with $_0$ in seconds, and $V_0 = C = 8.2$ 0.6. If the same t is repeated with free, one nds = 0:28 0:03, and sim ilar values for the other parameters: $V_0 = 667 \quad 21 \text{ K}$, $\log_{0} = 122 \quad 0.18$, and $V_0 = C = 7:7$ 0:7. This shows that the distribution g (V) suggested by the SPM is very adequate indeed. It also shows that can be xed at 1/4, which will be done for the rest of this paper. The rather high value obtained for $V_0 = C$ emphasizes that one should not neglect the cut-o in the asymmetry distribution. We return to this point below .

O ur analysis reveals a certain di culty in comparing the absolute size of the various curves. This can be related to some extent to the di erent polarizations of the waves in these measurements, or also to a small part to the di erent qualities of the silica samples employed.

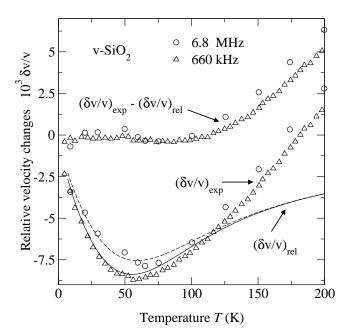


FIG.2: The data points of the two lower curves are relative velocity changes of v-SiO₂ taken from the literature, [6] for 660 kH z and [23] for 6.8 MH z. The solid lines show our calculation of the TAR contribution according to Eq. (9b) with C = 1:4 10³. The data points of the upper two curves show the experiment m inus the TAR contribution.

However, it seems more likely that it arises to a large part from calibration inaccuracies in some of these measurements. Indeed, discrepancies in the size of Q 1 are directly observed in com paring literature reports, for example for the TA-waves at 20 MHz in [1] and [25]. The di culty is also seen in comparing the LA to TA values of Q¹ in [23] and in [25]. W hile in the form er case it is the attenuations that have the sam e am plitudes for both LA and TA, in the latter it is the internal frictions which are practically the sam e for both polarizations. This cannot be reconciled as attenuation and friction di er by a factor proportional to the sound velocity, and the latter is ' 5900 m /s for LA and ' 3800 m /s for TA-waves at low T.W e also observed that the results at 660 kHz in [6] are tted extremely wellwith the same model param eters, provided one allows for a relatively sm all constant background contribution to Q 1 , equal to 0:1 10³. The values of C obtained for these various m easurem ents 10^3 in the case of [6] to 1:8 range then from 1:1 10 ³ for [1]. These variations in C do not seem correlated to either the m easuring frequency or the wave polarization, which is another reason to suspect calibration di culties.

It is necessary to obtain a more reliable value of C to analyze the B rillouin scattering data in the following Section. To this e ect we remark that velocity measurements are generally both accurate and precise, allowing to follow small changes in v=v with excellent accuracy. W e use two measurements of the LA wave velocity, one at 660 kHz from [6] and the other at 6.8 MHz from

[23]. The experimental values $(v=v)_{exp}$ are shown in Fig.2, together with continuous lines marked $(v=v)_{rel}$. These are calculated from the relaxation equation (9b) using the above values of V₀, c, and 0, together with $C = 1.4 \quad 10^3$. W ith the latter value, the dip around 50 K is completely accounted for. This is emphasized by the di erence $(v=v)_{exp}$ $(v=v)_{rel}$ also shown in Fig.2. Hence, we adopt for the following the coupling constant $C = 1.4 \quad 10^3$ which happens to fall within the range of values obtained by tting the various Q⁻¹ curves discussed above.

We now return to the small cut-o value $_{\rm C}$ ' 80 K which we obtained. This aspect has mostly been ignored by other workers. It was shown in [21] that it is necessary to include a cut-o to obtain a good t to the high-T tails in Fig.1. For example, forcing $_{C} = V_{0}$, the quality of the ts degrades appreciably above 70 K, especially for the highest curve. M ore im portantly, the calculated values of (v=v)_{rel} are then much too large to account properly for the dip around 60 K observed in Fig. 2. O byiously, by the virtue of the K ram ers-K ronig transform, $(v=v)_{rel}$ integrates over a large part of the distribution, which is the reason for this problem . One might wish to gain an intuitive picture of why c can be so much smaller than V_0 . To this e ect, one can consider the models of TAR drawn in Fig. 2 of [27]. We take as simplest examples model A, in which the two Si atom s of a Si O Sibond are too close, and m odel B, in which they are too far apart. In either case, a double well potential for the connecting oxygen results with a barrier height V that com es mainly from the separation of the two Si. This barrier can thus be quite high. On the other hand, the asym m etry is produced by the di erence in the wider environm ent of the two wells. In a hard glass, one m ight expect that these environm ents, which are dictated by the minimization of the energy, can be mostly quite similar. From these considerations, one intuitively anticipates that the ratio $V_0 = _C m$ ight depend signi cantly on the particular glass.

Finally, we remark that the temperature $T_{m\ ax}$ of the peak positions in Fig.1 depends linearly on \ln . A sim – ilar observation was already made in [27]. This typical A mhenius behavior supports TAR as the principal relaxation mechanism to describe Fig. 1, as opposed for example to incoherent tunneling that would lead to $T_{m\ ax}$ / as seen from Eq. (2.95) of [28].

IV. ANALYSIS OF BRILLOU IN SCATTERING RESULTS

H igh-resolution B rillouin scattering m easurements of the tem perature dependence of the LA-linewidth of vitreous silica have been reported in [29] and [12]. B oth experiments were performed near backscattering and below room T, using as exciting radiation the blue argon-laser line at $_{\rm L}$ = 488 nm. M easurements above room T are reported in [30]. These were performed at $_{\rm L}$ = 514 nm.

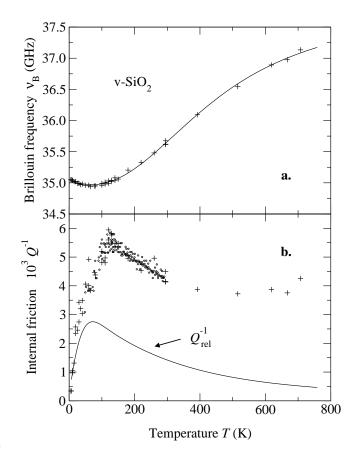


FIG.3: a: The data points are Brillouin shifts obtained on v-SiO₂ near backscattering, from [29] and [30]. The values of [30] have been rescaled to the blue argon-laser line, $_{\rm L}$ = 488 nm. The solid line is a guide to the eye. b: The internal friction derived from the Brillouin linewidths. The crosses are from [29] and [30], while the dots are from [12]. The solid curve shows the TAR contribution calculated from Eq. (9a) using the value of C determ ined from the velocities in Fig.2.

The Brillouin frequency shifts $_{\rm B}$ from [29] and [30], the latter rescaled to $_{\rm L}$ = 488 nm, are displayed in Fig. (3a) over the entire range of T.

The frequency widths extracted from the Brilbuin peaks in [29] and [30], after correction for the instrum ental broadening, have been converted to internal friction as shown in Fig. (3b). The internal friction reported by T ielburger et al. in [12] is also shown on the same gure. O ne notices the rem arkable agreem ent between these two independent determ inations. It emphasizes that Brilbuin scattering gives an absolute measurem ent of Q⁻¹, independent from calibrations, since it su ces to take the ratio of the Brilbuin full-width to the Brilbuin shift to extract Q⁻¹. This statem ent of course assumes that the spectroscopy can be performed with the required resolution, and in particular that the broadening produced by the nite collection aperture can be made su ciently sm all.

A lso shown in Fig. (3b) is the curve Q_{rel}^{1} calculated with Eq. (9a) for = 35 G H z and with the parameters

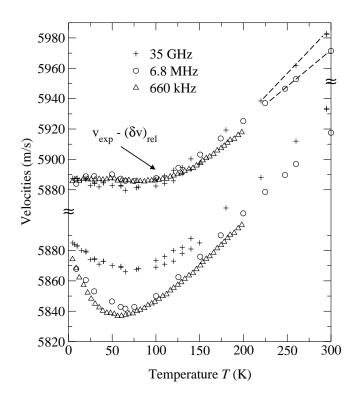


FIG. 4: The lower data points show the measured ultrasonic velocities from Fig. 2 together with the hypersonic velocity derived from Fig. (3a). The upper data points show the same velocities after subtraction of the TAR contribution. We note that after this subtraction there remains a small di erence between the slopes observed at high T for the two di erent frequencies. These slopes are shown by the dashed lines and they are discussed in Appendix B.

determ ined in Section III. It is evident that at B rilbuin frequencies TAR cannot account for the entire internal friction. The value C ' 1:4 10³ is con med by the B rilbuin velocity results explained below. However, even if one would allow oneself to arbitrarily double the coupling constant C, the line in Fig. 3 (b) would still not superpose the data points. In particular the peak in Q $_{rel}^{1}$ occurs at a lower T-value than the peak in the observed Q 1 . The di erence between the two curves is attributed to its largest part to the anham onic coupling of the LA-waves with the therm ally excited vibrationalm odes, as reported in (I) for densi ed silica glass.

The velocities are extracted from the B rillouin frequencies $_{\rm B}$ of Fig. (3a) using v = $_{\rm L}$ $_{\rm B}$ = 2n sin $_{\overline{2}}$, where n is the refractive index and is the internal scattering angle, here close to 180. To derive precise values on v(T), it is necessary to know n(T) with an equal precision. This inform ation has been derived from [31]. The results below 300 K are shown in Fig. 4, together with the velocities at 6.8 MHz from [23]. The relative changes reported in [6] have also been converted back to velocities using $v_0 = 5888$ m/s. Subtracting from all three curves the (v)_{rel} calculated from Eq. (9b), one observes that below 150 K all the data collapse quite well. This con ms

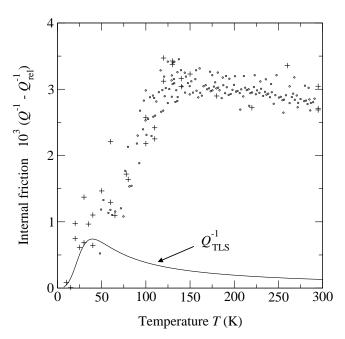


FIG. 5: The internal friction observed in B rillouin scattering after subtraction of the TAR contribution shown in Fig. (3b). The crosses are from [29] while the dots are from [12]. The solid line is a rough estim ate for the small tunneling contribution extrapolated from data presented in [32].

that the value of C is also correct at B rillouin frequencies. It also emphasizes that the -dependence in the depth of the dip around 70 K is well predicted by TAR. As explained in Section VIB, the velocity changes that are produced by the anharm onicity, $(v)_{anh}$, show little dispersion compared to the large dispersion in $(v)_{rel}$. Hence, they do not modify the above conclusion.

Figure 5 shows the di erence between the experim ental internal friction and the calculated TAR contribution. Similarly to the results on d-SiO₂ in (I), there is a region where the signal falls rapidly with decreasing T. How – ever, it does not seem to fall to zero su ciently fast. In spite of the large scatter in the experimental values, there is a hint for an additional contribution to Q¹ at low T, in the region from 20 to 60 K. At these hypersonic frequencies and temperatures, one can anticipate a contribution Q¹_{TLS} arising from the relaxation of two-level system s (TLS) by incoherent tunneling. Generally, Q¹_{TLS} (T) exhibits a plateau separating a regime

min 1 at low T < T from min 1 at higher T, as shown in [28] where min and T / $^{1=3}$ are dened. The position, extent, and height of this plateau are dependent, as emphasized in Fig. 6 of [32]. A coording to [28], the extent of the plateau should shrink to zero at su ciently high frequencies such that T > T , where T is a frequency independent characteristic tem perature m arking the end of the plateau region. In v-SiD₂, it has been observed that T ' 5 K [12]. The plateau becom es then a hump slightly above T. As shown in [32], for = 46 M Hz one should have T' 3 K. This value increases with $^{1=3}$, as con med from sound-damping data between 330 and 930 M Hz [33], showing a shoulder on the low T side of the TAR peak. Hence, at 35

GHz one expects T 30 K, giving a broad TLS hump centered around 40 K $.Q_{\rm TLS}^{-1}$ / T 3 below this hump, and $Q_{\rm TLS}^{-1}$ / T 1 above it [28]. Extrapolating the observations reported in [32] we posit

$$Q_{TLS}^{1} = \frac{13 \cdot 10^{3}}{(30=T)^{3} + (T=30)}$$
 (12)

as a rough estim ate for this relatively sm all contribution to Q 1 . This curve, which peaks around 40 K , is shown in Fig. 5. The di erence

$$Q_{anh}^{1} = Q^{1} \qquad Q_{rel}^{1} \qquad Q_{TLS}^{1}$$
 (13)

will be used below to analyse the anham onic damping. Since there seems to be a small tunneling contribution Q_{TLS}^{-1} , then there ought to be by the K ram ers-K ronig relation a corresponding contribution (v)_{TLS}. As shown in Eq. (2.96) of [28], this should produce at high-T a frequency dependent term in T ln . As shown in Appendix B, there are reasons to believe that it is this term that produces the di erence in slopes indicated by short dashed lines in Fig. 4.

To conclude, we nd a relatively large Q_{anh}^{-1} at hypersonic frequencies. It is of the same order of magnitude as Q_{rel}^{-1} . The small additional term Q_{TLS}^{-1} that has been discussed above is a correction of minor in portance compared to Q_{anh}^{-1} , as obvious from Fig. 5.

V. THE THERMAL RELAXATION TIME

In the spirit of (I) we now analyze the anharm onic damping with the expression

$$Q_{anh}^{1} = A \frac{th}{1 + \frac{2}{th}^{2}};$$
 (14)

where the is the mean lifetime of the therm almodes and A (T) = ${}^{2}C_{v}Tv=2v_{D}^{3}$ is the prefactor given in Eq. (5b) of (I), with C_v the speci c heat per unit volume and v_D the Debye velocity. We remark that all quantities entering A (T) are known, except for the mean-square average G runeisen parameter 2 . Thus we can directly plot the quantity ${}^{2}Q_{anh}^{1}$ = A as it is independent from The result obtained using the values ${\rm Q\,}_{\rm anh}^{-1}$ taken from Fig. 5 is drawn in Fig. (6a). Points below 60 K are not shown as the data is too noisy at low T to be signi cant after division by A / C_vT. This plot exhibits a peak $_{\rm th}$ = 1. From the height of this peak one reads for ² ' 3:6. W ith this determ ination, Eq. (14) can then be solved for $_{\rm th}$, and thus for $_{\rm th}$. The procedure is explained in Appendix C. The result is shown in Fig. (6b). One observes that $_{\rm th}$ (T) is proportional to T 2 over the

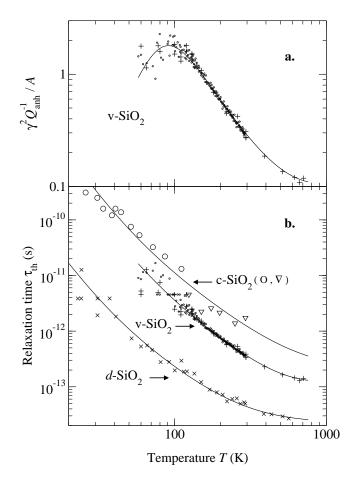


FIG.6: a: The anharm onic damping contribution scaled by A (T)= 2 . The solid line is a guide to the eye calculated from the corresponding line in b. The peak is located at T_{M ax} (see A ppendix C) and its height gives 2 =2.b: The values of the for v-SiO₂ obtained from the data in a after solving Eq. (14). D ata for x-cut crystal quartz and d-SiO₂ from (I) are shown for comparison. The lines for v-SiO₂ and d-SiO₂ are guides to the eye which are sum s of negative powers of T, while the line for c-SiO₂ is calculated from Eq. (15).

main part of the data, from 100 K to 300 K.At higher T, th tapers o, while at lower T there is a hint that that th (T) might diverge faster than in T². The solid line is a guide to the eye which is a sum of powers of T. The same law is then used to trace the guide to the eye in Fig. (6a).

In Fig. (6b) we have traced for comparison the values of the relaxation time of the therm alm odes for two other cases. Firstly, we observe that $_{\rm th}$ (T) obtained in (I) for densi ed silica glass, d-SiD₂, is substantially shorter than in v-SiD₂. However, it shows a very similar functional dependence on T. Secondly, in order to deepen the understanding, we applied the same m ethod of analysis to data on the LA-m ode of X-cut crystal quartz, c-SiD₂. We used to thise ect the attenuation coe cient m easured by Bom m el and D ransfeld at 1 G H z [34]. At tem peratures above 150 K, we com pleted these data using the width of the Brillouin line reported in [35]. These data were analyzed sim ilarly to Fig. (6a) leading to 2 ' 0:95. The corresponding th (I) is shown in Fig. (6b). In this case, the line through these points is not a guide to the eye as for the two glasses, but it is an independent determ ination of th (I) using the well-known kinetic expression for the therm al conductivity,

$$= \frac{1}{3} C_v v_D^2 th :$$
 (15)

We observe that in this case the value of $_{\rm th}$ derived from (line) is in remarkable agreement with that obtained from the measurement of anharm onic damping of the acoustic modes. This emphasizes the physical signicance of $_{\rm th}$: it really is the mean lifetime of the excitations in the thermal bath which at su ciently high T is entirely controlled by Um klapp (U) processes. As pointed out in [36], this produces a relaxation proportional to the phonon population, and thus at high T one has $_{\rm th}$ / T 1 . At intermediate T, where C $_{\rm v}$ / T and / T 1 , Eq. (15) indicates that $_{\rm th}$ / T 2 . This is indeed observed in c-SiO $_2$ over a large range of T, as seen in Fig. (6b).

Equation (15) assumes propagating therm alphonons. For this reason, it becomes invalid in glasses at soon as T increases beyond the therm al conductivity plateau located around 10 K in v-SiO2. However, we rem ark that the functional dependence $_{\rm th}$ (T) observed in the two glasses is very similar in shape to that in $c-SiO_2$. We have no simple explanation for this. In glasses, there are two competing e ects that modify the picture presented above. On the one hand, the strict quasi-m om entum conservation which is invoqued in U-processes is strongly relaxed, and this must greatly enhance the interactions in the therm albath, decreasing the This could account for the observed di erence between crystal and glasses. On the other hand, the therm alm odes are not expected to be propagating plane-waves but they are at best diffusive. This restricts the spatial extent of the modes, greatly decreasing their overlap and thereby their interactions, which increases the We believe it is the latter e ect which produces the much longer the in v-SiO $_2$ compared to $d-SiO_2$. Indeed, in $d-SiO_2$ the boson peak is strongly reduced [37]. This increases the crossover frequency ! co beyond which the acoustic excitations becom e di usive, as recently con m ed by inelastic x-ray scattering [38]. This in turn increases the mean spatial extent of the modes and thereby their interactions leading to a faster therm alization.

Finally, we remark that the above analysis gives values for the m ean G runeisen parameter 2 . We end 0.95 for the LA-mode of x-cut quartz, 3.6 for v-SiO₂, and 8 for d-SiO₂. In the case of crystal quartz, the agreement between the line calculated from the thermal conductivity and that obtained from Q 1 gives a solid support for the value of 2 . Unfortunately, one cannot make a similar comparison for the glasses.

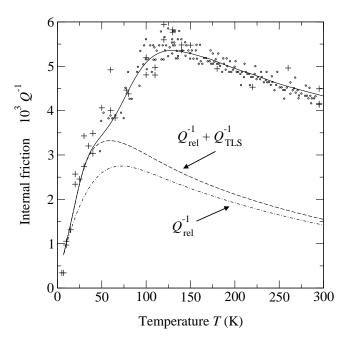


FIG. 7: The internal friction at 35 GHz from the Brillouin scattering m easurements of [12] () and [29] (+). The solid curve is the entire adjustment made here which is the sum of three contributions $Q_{rel}^{-1}, Q_{TLS}^{-1}$, and Q_{anh}^{-1} .

VI. SUMMING-UP

A. The internal friction

Figure 7 sum marizes the present analysis of the internal friction observed in v-SiO₂ with B rillouin scattering around 35 G Hz. One identi es two main contributions: Q_{rel}¹ arising from thermally activated relaxation and Q_{anh}¹ = Q¹ (Q_{rel}¹ + Q_{TLS}¹) which results from network viscosity. A round room T, Q_{anh}¹ is nearly twice as large as Q_{rel}¹. The incoherent tunneling contribution Q_{TLS}¹, if it really exists at these high frequency and tem – peratures, mainly produces the smallhum p around 40 K. A lthough there is a hint for such a feature in the data shown in Fig. 7, it would need to be con med by more precise measurements. A lso, we neglected in this analysis a possible contribution arising from the quasi-harm onic oscillators of the soft-potential model [17]. This is explained in Appendix D.

As is increased beyond 35 G Hz, we nd that the value Q_{rel}^{-1} calculated with Eq. (9a) saturates. This saturation essentially results from the cut-o in f (). For example at room T, Q_{rel}^{-1} does not increase beyond 1.5 10^3 . On the other hand, at su ciently high T, Q_{anh}^{-1} continues to grow with according to $Q_{anh}^{-1} = A_{th}$ which applies as long as the 1. We also nd that A th is practically constant from 100 to 300 K. For these reasons, the total Q^{-1} becomes dominated by network viscosity, it continues to increase proportionally to up to several hundred G Hz, and it is nearly T-independent from 100 K

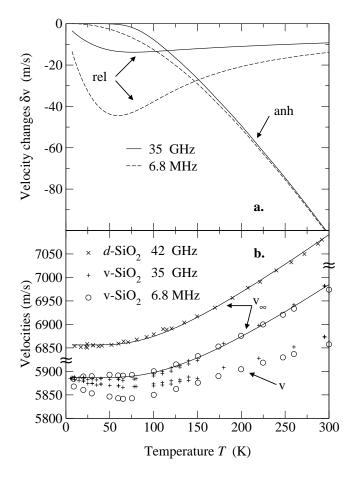


FIG.8: a: Calculated velocity changes produced by TAR (rel) and by network viscosity (anh) at two typical frequencies. b: The m easured velocities at the same frequencies (lower data points) and the unrelaxed values v_1 after correction for TAR and network viscosity (upper data points). The line is a t of v_1 to W achtman's equation as a guide to the eye. The v_1 data for d-SiO₂ from (I) are also shown for com parison.

to 300 K. This is in excellent agreem ent with the results on acoustic propagation reported for v-SiO₂ thin Im sby Zhu, M aris, and Tauc [39]. These authors nd that the m ean free path, '¹, grow sin ² from 30 G H z to 300 G H z, and that it is nearly independent of T from 80 to 300 K. Since '¹ Q¹ =v, the dom inance of Q¹_{anh}, its grow th / , and its near constancy in T, fully account for the data reported in [39]. Our predictions are also fully consistent with three data points measured with UV B rillouin scattering from 50 to 100 G H z [40, 41].

On the other hand, at ultrasonic frequencies, i.e. much below 35 G H z, the contribution of Q_{anh}^{-1} which decreases proportionally to becomes completely negligible com – pared to Q_{rel}^{-1} . This justies the analysis based only on TAR that was performed in relation with Fig.1.

B. The velocity changes

Figure (8a) shows the velocity changes calculated from Eq. (9b) for TAR, and using

$$\frac{v}{v}_{anh} = \frac{A}{2} \frac{1}{1 + \frac{2}{th}}$$
 (16)

for the network viscosity, this at two typical frequencies. One notices that the increase in from 6.8 MHz to 35 GHz leads to a large reduction of $jv_{rel}j$. On the other hand, j $v_{\text{anh}}\,j$ although quite large above 100 K , changes relatively little with . In particular, the dashed curve is entirely in the regime th 1, so that it is practically independent of at lower -values. This justi es the approach used to determ ine C in Fig. 2 where the anharm onicity contribution was simply neglected. At sufciently high-T, anham onicity always leads to a quasilinear decrease of $v \ w$ ith T , very sim ilar to what is observed in crystals [42, 43]. This has been seen in ultrasonic measurements in a large number of glasses, e.g. in [44] where this e ect is interpreted as such. At these frequencies, one is in a regime where the velocity changes are dom inated by network viscosity while the dam ping mainly originates from TAR. It is generally necessary to go up to Brillouin frequencies to observe in Q¹ both contributions simultaneously.

The velocity changes in tetrahedrally coordinated glasses, in particular in v-SiO₂ and in d-SiO₂, are more complex than described above. Fig. (8b) shows the observed velocities, v, and the unrelaxed value that is corrected for both TAR and network-viscosity dispersions, $[(v)_{rel} + (v)_{anh}]$. As observed, the exper $v_1 = v$ in ental points collapse to a v_1 which on this scale is essentially -independent. However, rather than being constant, v_1 increases considerably with T. In the same gure, the results obtained in (I) for d-SiO 2 are shown for comparison. Both solid lines are guides to the eye obtained by an ad hoc adjustment to W achtman's equation [45]. The behaviour of v_1 is remarkably similar in both glasses, pointing to an anom alous hardening of silica with increasing T. As discussed in (I), the earlier proposal that this is a manifestation of large structural inhom ogeneities [46] is not supported by observations. The anom alous hardening has recently been attributed to a progressive local polyam orphic transition associated with abrupt rotations of random ly distributed SiO -Sibonds, found in simulations [47]. Therm alagitation would redistribute the SiO-Sibond angles in con gurations where they are m ore resilient. How ever, contrary to [48], our results indicate that a very sim ilar mechanism would then be active in permanently densi ed silica. Repeating the warning made in (I), although v_1 has a clear physical signi cance, it would be nearly in possible to perform at the moment an experiment to directly measure it. This is even more so in v-SiO₂ than in d-SiO₂, owing to the low er $!_{co}$ of the form er glass.

C. The tunneling strength

It remains to compare the value $C = 1:4 \quad 10^3$ found in Section III to the tunneling-strength parameter C ' $3:0 \quad 10^4$ from the literature. To do this, both values are inserted in Eq. (11) to calculate the cut-o energy W that applies to the present case. We nd W ' 7 K, as opposed to the TLS value W ' 4 K derived from the low-T speci c heat data [16]. Such a larger value of W was already reported, resulting from a similar analysis in [18]. Its origin was convincingly explained there as arising from a di erent weighing of the distribution of W -values, in W ⁴ for the speci c heat, and in W ¹ for the ultrasonic absorption. The value of C is thus fully in line with expectations.

VII. DISCUSSION

W e have shown that ultrasonic and hypersonic dam ping and dispersion in vitreous silica at temperatures above the quantum regime originate in at least two main processes: them ally activated relaxation and network viscosity. These have dierent and T dependences which leads to a non-trivial variation of the scattering linewidth with . At a given T, TAR dominates the dam ping at low, while anharm onicity dom inates at sufciently high . Between these two regimes there occurs a \dynam ical crossover" which for v-SiO 2 at room T falls near our Brillouin frequency, as shown in Fig. 10 of [39] and con med in Fig. 7 above. Above this crossover, the damping is dominated by $Q_{anh}^{1} = A_{th}$, which implies that / ². As is increased far beyond optical Brillouin frequencies, another broadening mechanism eventually com es into play. A round 300 GHz, one expects the onset of a new contribution to Q $\,^1$, grow ing with a higher power of , possibly in ³, as suggested in [49]. This additional contribution is currently thought to result from the hybridization of the acoustic modes with boson-peak excitations [50, 51], as inelastic x-ray scattering observations on d-SiO 2 strongly suggest [38, 52]. Unfortunately, inelastic x-ray scattering at su ciently sm all scattering vectors and with su ciently high energy resolution could not yet be perform ed on v-SiO₂ to settle the issue of this onset. This hybridization eventually leads to the Io e-Regel crossover at $!_{co}$, above which the excitations have lost their plane-wave character. Then, the wave-vector q does not rem ain a good label for the modes which are at best di usive [53]. The excitations of the therm al bath are expected to be of that nature in glasses, as discussed in Section V.

Power laws / ⁿ, or / qⁿ which is equivalent as long as the frequency is well below the Io eRegel limit so that q /, are often employed to represent the dam ping data (). As just explained, / ² is a reasonable approximation in the region between the dynam ical crossover and the Io eRegel one. On the opposite, such laws should be viewed as quite rough approximations in the TAR-dom inated regime. The reason is that the dependence of on predicted by Eq. 9a is more complicated. It cannot be written simply in terms of a T-dependent exponent n(T). For example, in v-SiO₂ at room T, a value n = 1:3 is given in [54], while n = 1:3is derived from [7]. We conclude that power laws in the TAR-dom inated regime are ad hoc devices which only represent approximately the data, especially if the latter are su ciently noisy to mask the disagreements.

At this point, it is legitimate to ask to what extent anharm onicity m ight be in portant to sound dam ping in other glasses. The answer to this question depends on two factors: i) the strength, density, and distribution of the relaxing defects; ii) the strength of the anham onicity. It is conceivable that in glasses that contain a large quantity of defects up to high values of V_0 and $_C$, TAR would mask the anharm onicity. In that case the dynam ical crossover m ight move up to nearly $!_{co}$, so that a reqime / ² m ight not be observable at all. We have found such a case in lithium diborate, v-Li₂B₄O₇ [51]. This type of situation is expected for most polymers in which the tunneling strength C is quite large [22]. On the other hand, there exist m any glasses or am orphous materials for which C is quite small, wellbelow 10 4 [22]. Such are the am orphous group IV sem iconductors, C, Si, and Ge. In that case, the anham onicity is expected to dom inate over a considerable range of and a calculation to that e ect has already been performed [55]. Of the tetrahedrally coordinated glasses, it will be particularly interesting to reinvestigate v-GeO₂ and v-BeF₂. Di culties met in obtaining a quantitative description of damping and dispersion in germania on the basis of TAR alone, described in [10], might nd their resolution by including in the analysis the cut-o $_{\rm C}$ and the network-viscosity contribution.

To summarize, TAR essentially explains acoustic damping results in silica glass up to a few GHz. At higher frequencies, the anham onic coupling of hypersound to the modes that form the entire them al bath becomes progressively dominant. This conclusion, in line with previous observations [23] and simulations [55], corrects statements to the contrary offen found in the literature, e.g. in [7, 8, 9]. The anham onicity which in our view produces Q_{anh}^{-1} is a coupling of sound to the whole bath, in addition to the relatively sm all fraction ofm odes form - ing the boson peak. This process, which we call network viscosity, is in a way quite similar to the usual lattice viscosity of crystals.

APPENDIX A: ESTIMATING EQS. (9)

For the M arquardt-Levenberg adjustment of Eqs. (9), it is convenient to use the parameters C, V_0 , log_{10} , , and . Taking as integration variable x $V=V_0$, and de ning the auxiliary variables $V_0=T$ and y 0, Eq. (9a) becomes

$$Q_{rel}^{1} = C \left(\begin{array}{c} p_{\overline{2}} \\ 2 \end{array} \right) \left(\begin{array}{c} z \\ 0 \end{array} \right) x \exp \left(\frac{1}{2} x^{2} \right) \frac{y \exp (x)}{1 + y^{2} \exp (2 x)} dx :$$
 (A1)

G ood results are obtained with a simple trapezoidal integration, taking a geometric progression for the vector of x-values. We used x starting at ' 10⁴ and ending at ' 10, in steps of 1%. Eq. (9b) is handled similarly.

APPENDIX B:VELOCITY CHANGES DUE TO IN COHERENT TUNNELING

O ne observes on the upper curves of F ig. 4 that there is a small di erence in the high tem perature slopes for the two di erent frequencies. The origin of this effect m ight be in the velocity dispersion associated, by the K ram ers K ronig transform, with the relatively small damping $Q_{\rm TLS}^{-1}$ produced by incoherent tunneling. At high T, the damping is given by the third equation (2.94)

of [28],

$$Q_{TLS}^{1} = \frac{C}{4 r_{m in}} \frac{\sim}{k_{B} T}$$
 : (B1)

The corresponding v_{TLS} is derived from the third equation (2.96) of [28], which gives for the -dependent part

$$v_{TLS}$$
 ' 0:45 $\frac{C}{T}$ (ln) T : (B2)

The temperature T marks the end of the low -T plateau region in Q¹ and it is given by Eqs. (2.78) and (2.79) of [28]. Owing to the logarithm ic dependence in (B2), it is the di erence of slopes at two frequencies which is signi cant,

$$\frac{(v_{TLS})}{T} = \frac{(v_1)_{TLS}}{T} \cdot 0.45 \frac{C}{T} \ln(t_1 = t_2) :$$
(B3)

W ith the values in Fig. 4, and calculating T following [28], one nds C 7 10^5 . As expected, this is smaller than the tunneling strength found from specic heat m easurements at low temperatures [22], the reduction being of the order of ____T. Hence, it is not unreasonable to assign the di erence in slopes observed at high-T in Fig. 4 to the K ram ers-K ronig transform of Q ____TLS}.

APPENDIX C:SOLVING EQ. (14) FOR THE RELAXATION TIME

It is in principle trivial to solve the quadratic equation $y = x = (1 + x^2)$ for x th in terms of the measured $Q^{1} = A$. However, in aginary roots do occur in the V region around x = 1 owing to uctuations in the data leading to some points for which y > 1=2. These are the points whose ordinate lies above the maximum of the solid curve drawn in Fig. (6a). For these data points, we simply replaced x by 1, as the nearest real solution. This produces a line of data points with $_{th} = 1 = in$ the presentation of Fig. (6b). For the data points with y < 1=2, one must select between the upper and the lower root of the quadratic equation. This is set by the location of the maximum in the solid curve, $T_{M ax}$. For $T < T_{M ax}$, the upper root applies since the since

the lower root applies at higher tem peratures.

APPENDIX D:ANOTHER POSSIBLE SOURCE OF DAMPING

We have not considered the damping arising from the weak anham onicity of the nearly ham onic oscillators (HO) of the soft potential model in the dom ain > 0 [17]. This contribution should be most active at \interm ediate" frequencies. In v-SiO₂, its strength has actually been predicted to be largest near our Brillouin frequency [17]. It must be noted that the entire (;T)-dom ain covered by the propagating pulse measurements of [39] falls within this \intermediate" frequency rapge where the additional damping obeys Q_{HO}^{1} / CT = [17]. If the strength of Q_{HO}^{1} would be su cient, one should de nitely notice its e ect on the (;T)-dependence of the mean free path reported in [39] from 80 to 300 K and from 30 to 300 GHz. On the contrary, the mean free path is found practically ², in agreement T-independent and it increases / with the network-viscosity contribution. It seems thus justi ed to neglect Q $_{\rm H\,O}^{-1}\,$ in our analysis of the B rillouin results up to 300 K. The diculty in estimating the size of Q_{HO}^{-1} apparently lies in nding the proper value

for the tunneling-strength parameter C that applies to it. The value C = 3.0 10⁴, appropriate for TLS at very low temperatures [22], is certainly too large here. Indeed, using this value in Eq. (3.18) of [17], we calculate $Q_{\rm HO}^{-1}$ ' 5 10⁵ T (K), which at 300 K is larger than the entire Q⁻¹ observed. >From an analysis of heat-release m easurem ents there are grounds to adopt here a value of C which is at least ve times sm aller [56].

- [L] O L. Anderson and H E. Bommel, J. Am. Ceram. Soc. 38, 125 (1955).
- [2] P.W. Anderson, B.J. Halperin, and C.M. Vanna, Phil. Mag. 25, 1 (1972).
- [3] W A.Phillips, J.Low Temp.Phys. 7, 351 (1972).
- [4] J. Jackle, Z. Physik 257, 212 (1972).
- [5] J. Jackle, L. Piche, W. A mold, and S. Hunklinger, J. Non-Cryst. Solids 20, 365 (1976).
- [6] K.S.G ilroy and W. A.Phillips, Phil.M ag. 43, 735 (1981).
- [7] J. W iedersich, S.V. Adichtchev, and E. Rossler, Phys. Rev.Lett. 84, 2718 (2000).
- [8] J.W iedersich, N.V. Surotsev, V.N. Novikov, E.Rossler, and A.P. Sokolov, Phys. Rev. B 64, 064207 (2001).
- [9] N.V. Surotsev, V.K. Malinovsky, Yu.N. Palyanov, A.A. Kalinin, and A.P. Shebanin, J. Phys.: Condens. Matter 16, 3035 (2004).
- [10] J.Hertling, S.Bae ler, S.Rau, G.Kasper, and S.Hunklinger, J.Non-Cryst. Solids 226, 129 (1998).
- [11] W A.Phillips, Rep. Prog. Phys. 50, 1657 (1987).
- [12] D. Tielburger, R.Merz, R.Ehrenfels, and S.Hunklinger, Phys. Rev. B 45, 2750 (1992).
- [13] R O. Pohl, in Am orphous Solids: Low-Tem perature Properties, W A. Phillips Ed. (Springer, Berlin, 1981) pp.27-52.
- [14] V G .Karpov, M J.K linger, and F N .Ignat'ev, Sov.Phys. JETP 57, 439 (1983).
- [15] M A. Il'in, V G. Karpov, and D A. Parshin, Sov. Phys. JETP 65, 165 (1987).
- [16] U. Buchenau, YuM. Galperin, V L. Gurevich, D A. Parshin, M A. Ramos, and H R. Schober, Phys. Rev. B 46, 2798 (1992).
- [17] D A . Parshin, Phys. Solid State 36, 991 (1994).
- [18] R. Keil, G. Kasper, and S. Hunklinger, J. Non-Cryst. Solids 164-166, 1183 (1993).
- [19] M .A bram ow itz and IA .Stegun, H andbook of M athem aticalFunctions (D over, N ew York, 7th P rinting 1970), Ch. 19, particularly p. 687.
- [20] L.G il, M A.Ramos, A.Bringer, and U.Buchenau, Phys. Rev.Lett. 70, 182 (1993).
- [21] J.P. Bonnet, J. Non-Cryst. Solids 127, 227 (1991).
- [22] R.O. Pohl, X iao Liu, and EJ. Thompson, Rev. Mod. Phys. 74, 991 (2002).
- [23] R. Vacher, J. Pelous, F. Plicque, and A. Zarem bow itch, J. Non-Cryst. Solids 45, 397 (1981).
- [24] P.Debye and F.W. Sears, Proc. Natl. A cad. Sci. USA, 18,409 (1932).
- [25] R E. Strakna and H.T. Savage, J. Appl. Phys. 35, 1445 (1964).
- [26] K S. Gilroy and W A. Phillips, J. Non-Cryst. Solids 35& 36, 1135 (1980).
- [27] S.Hunklinger and W.A.mold, in Physical Acoustics, Vol.

Even so, the resulting Q_{HO}^{-1} is still too large to agree with the results of [39]. Our Brillouin m easurements up to 700 K shown in Fig. (3b) suggest that there could be a small contribution / T that starts being felt above

400 K. This contribution would then be of the order of 10 6 T (K), which implies a very small e ective C for this particular damping mechanism.

X II, edited by W P. Mason and R N. Thurston (A cadem ic Press, New York, 1976), pp. 155-215.

- [28] S.Rau, C.Enss, S.Hunklinger, P.Neu, and A.W urger, Phys. Rev. B 52, 7179 (1995).
- [29] R. Vacher and J. Pelous, Phys. Rev. B 14, 823 (1976).
- [30] J. Pelous and R. Vacher, Solid State Commun. 18, 657 (1976).
- [31] R M .W axler and G W .C leek, J.Res. Nat. Bur. Stand. (U S.) 75A, 279 (1971).
- [32] K A. Topp and D G. Cahill, Z. Phys. B 101, 235 (1996).
- [33] C K. Jones, P.G. K lem ens, and J.A. Rayne, Phys. Lett. 8, 31 (1964)
- [34] H E. Bom m el and K. D ransfeld, Phys. Rev. 117, 1245 (1960).
- [35] J.P. Bonnet, M. Boissier, and A. Ait Gherbi, J. Non-Cryst. Solids 167, 199 (1994).
- [36] J.M. Zim an Electrons and Phonons Oxford Clarendon Press 1960
- [37] Y. Inam ura, M. Arai, O. Yam am uro, A. Inaba, N. Kitam ura, T. O tom o, T. M atsuo, S M. Bennington, and A C. Hannon, Physica B 263 & 264, 299 (1999).
- [38] B. Ru e, M. Foret, E. Courtens, R. Vacher, and G. Monaco, Phys. Rev. Lett. 90, 095502 (2003).
- [39] T.C. Zhu, H.J. Maris, and J. Tauc, Phys. Rev. B 44, 4281 (1991).
- [40] C. M asciovecchio, A. Gessini, S. Di Fonzo, L. Com ez, S.C. Santucci, and D. Fioretto, Phys. Rev. Lett. 92, 247401 (2004).
- [41] P.Benassi, S.Caponi, R.Eramo, A.Fontana, A.Giugni, M.Nardone, M.Sampoli, and G.Viliani, Phys.Rev. Lett. 71, 172201 (2005).
- [42] Landolt-Bornstein, New Series, Group III, Vol. 1 (Springer-Verlag, Berlin, 1966).
- [43] JA.Garber and A.V.Granato, Phys. Rev. B 11, 3990 (1975).
- [44] T N. C laytor and R J. Sladek, Phys. Rev. B 18, 5842 (1978).
- [45] O L.Anderson, Phys. Rev. 144, 553 (1966).
- [46] M N. Kulbitskaya, S.V. Nemilov, and V A. Shutilov, Sov. Phys. Solid State, 16, 2319 (1974).
- [47] Liping Huang and J. Kie er, Phys. Rev. B 69, 224203 (2004).
- [48] Liping Huang and J. Kie er, Phys. Rev. B 69, 224204 (2004).
- [49] R. Vacher, J. Pelous, and E. Courtens, Phys. Rev. B 56, R 481 (1997).
- [50] V L. Gurevich, D A. Parshin, and H R. Schober, Phys. Rev. B 67, 094203 (2003).
- [51] B.Ru e, G.Guim bretiere, E.Courtens, R.Vacher, and G.Monaco, submitted (arX is cond-m at/0506287, 01 Sep 2005).

- [52] E. Courtens, M. Foret, B. Hehlen, B. Ru e, and R. Vacher, J. Phys.: Condens. M atter 15, S1279 (2003).
- [53] J. Fabian and P.B. Allen, Phys. Rev. Lett. 77, 3839 (1996).
- [54] T. Scopigno, S.N. Yannopoulos, D.Th. Kastrissios, G. Monaco, E. Pontecorvo, G. Ruocco, and F. Sette, J.

Chem.Phys.118,311 (2003).

- [55] J. Fabian and P.B. Allen, Phys. Rev. Lett. 79, 1885 (1999).
- [56] D A. Parshin and S. Sahling, Phys. Rev. B 47, 5677 (1993).